

Patent Abstracts of Japan

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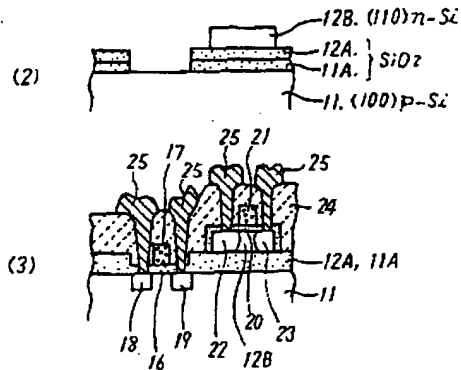
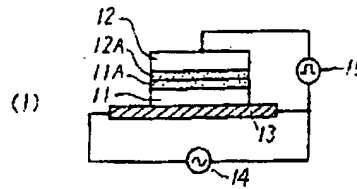
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TITLE : MANUFACTURE OF
SEMICONDUCTOR DEVICE



ABSTRACT : PURPOSE: To speed up a CMOS element by a method wherein an n-channel FET with a channel region in a plane (100) is built in p-type silicon and a p-channel FET with a channel region in a plane (100) is formed in n-type silicon.

CONSTITUTION: A p-Si substrate 11 of a plane index (100) and an n-Si substrate 12 of a plane index (100), mounted with approximately 3000 Å thick SiO₂ layers 11A and 12A, are put together on their SiO₂ surfaces and placed on a carbon heater 13. The substrates 11 and 12 are heated and then exposed to a pulse voltage for adhesion. The substrate 12 is thinned out by lapping and etching. The substrate 12 is subjected to another etching after which only an island-geometry element-forming n-Si region 12B is retained and the SiO₂ layer 12A is exposed. A p-channel FET is built on the n-Si region 12B, the SiO₂ layers 12A and 11A are locally removed for the exposure of the substrate 11 for the construction of an n-channel FET thereon. This design enhances a CMOS element in its operating speed.

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